Applicant(s)/Patent Under Application/Control No. Reexamination 10/679,697 LEE ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 Thoi V. Duong 2871 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY US-Α В US-С US-D US-Ε US-F US-US-G US-Н USı J US-Κ US-L US-М US-**FOREIGN PATENT DOCUMENTS** Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY JP 09-325328 12-1997 Ν Japan Hakoda et al. 0 Ρ Q R s T **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

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